

<b>Notice of References Cited</b>	Application/Control No. 10/679,367	Applicant(s)/Patent Under Reexamination YOKOYAMA ET AL.	
	Examiner Sin J. Lee	Art Unit 1752	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0054287	03-2003	Yasunami et al.	430/270.1
*	B	US-2003/0039916	02-2003	Adegawa et al.	430/270.1
*	C	US-2001/0041769	11-2001	Iwasawa et al.	524/588
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP1-197520	08-1989	Japan	Watabe et al.	N/A
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chemical Abstract 112:66778 (English abstract for JP 1-197520).
	V	JPO English abstract for JP 1-197520.
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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